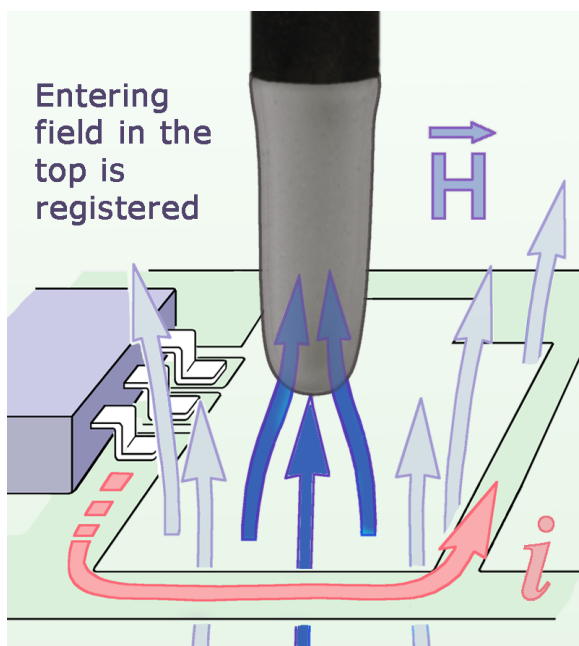


XF-B 3-1

H-Field Probe 30 MHz up to 6 GHz

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Short description

The measurement coil of the XF-B 3-1 H-field probe is set at a 90° angle to the probe shaft.

By positioning the probe head vertically, the measurement coil touches the surface of the printed circuit board directly. This allows for use at places on the surface of printed circuit boards, which are typically hard to access, e.g. between large components of switching controllers.

The XF-B 3-1 is a passive near-field probe which detects magnetic field lines emitted from the measured object at 90°. Magnetic field lines which enter the probe laterally are not detected.

In contrast to the XF-R 3-1 H-field probe, its coil is positioned in the probe tip at a 90° angle.

The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	≈ 2 mm
Probe head dimensions	$\varnothing \approx 4$ mm
Connector - output	SMA, female, jack
Weight	15 g

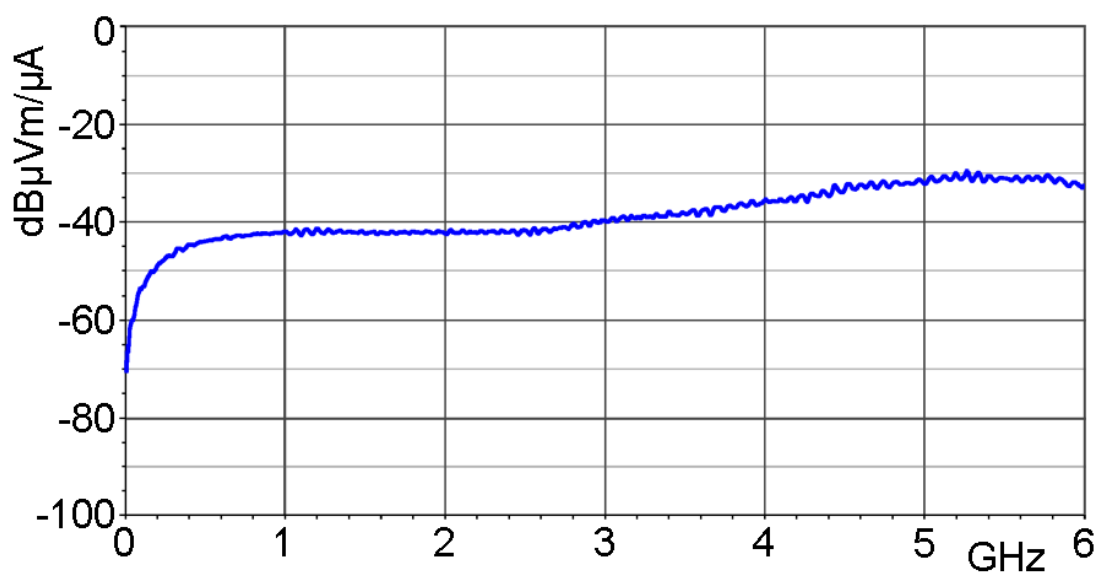


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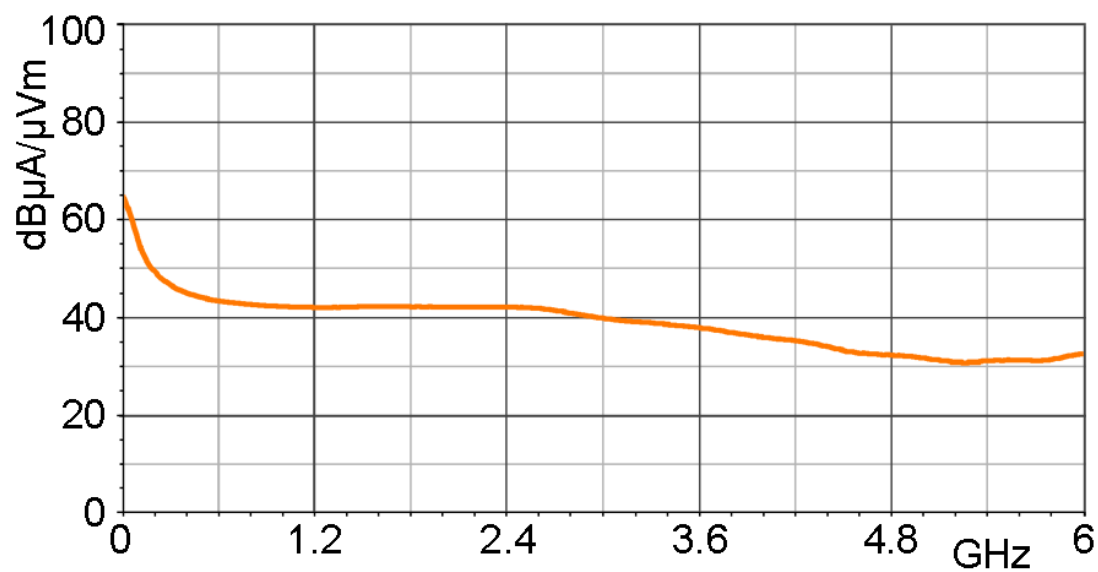
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Frequency response [dB μ V] / [dB μ A/m]



H-field correction curve [dB μ A/m] / [dB μ V]

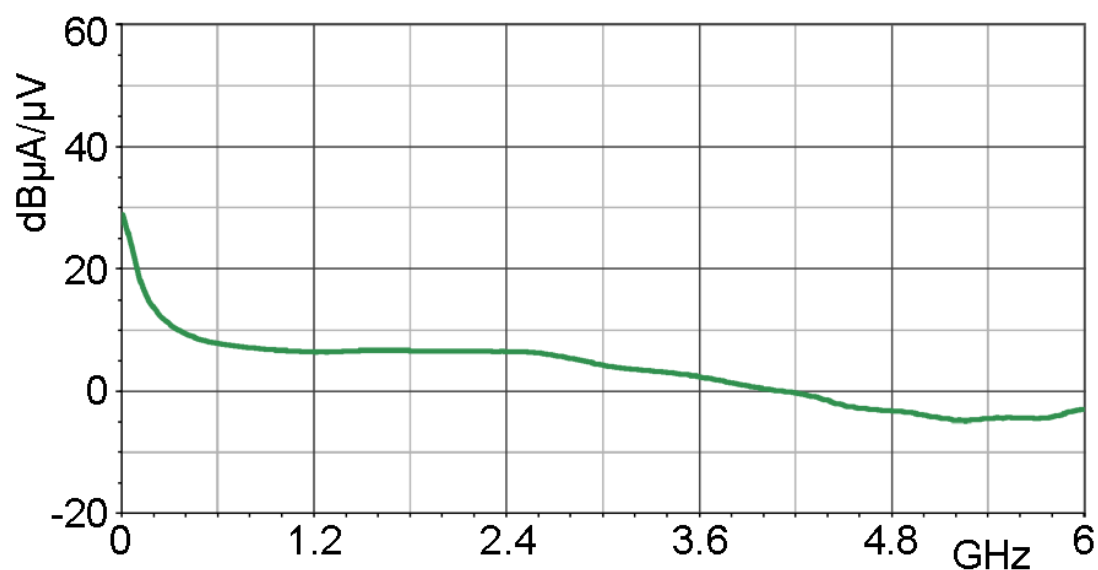


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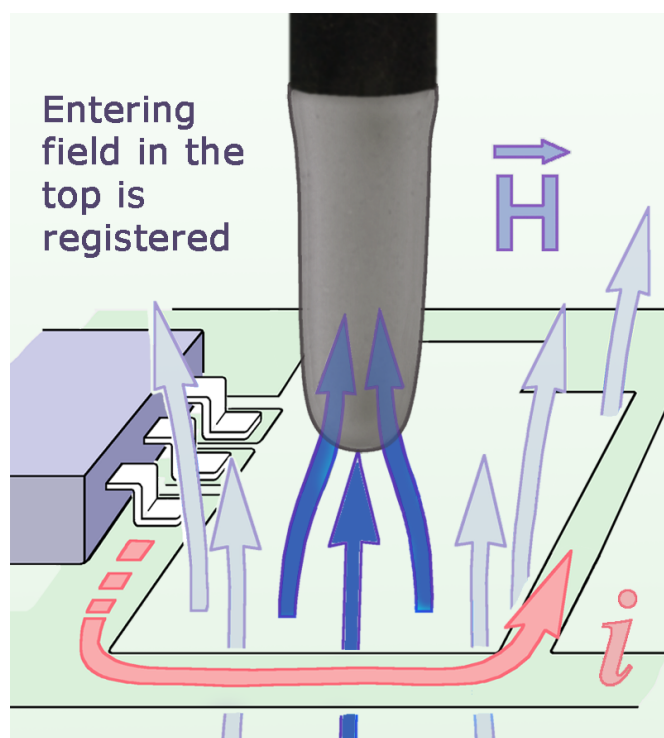
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Current correction curve [dB μ A] / [dB μ V]



Measuring principles



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Probe head

